

# Catching Failures in Robust Phase Estimation (originally: Calibration for Single-Qubit Gates using Robust Phase Estimation)

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# Quantum process characterization

If we want to do gate-based quantum computation...

⇒ Need to measure errors in a universal set.

Local, unitary errors (and also decoherence, crosstalk, etc.)

- Process tomography: inefficient for specific parameters, typically needs perfect SPAM
- Gate set tomography: powerful, few assumptions, but even more inefficient
- Randomized benchmarking: inefficient for specific parameters
- **Robust phase estimation**<sup>1</sup> (RPE): Heisenberg-limited, handles imperfect SPAM, nonadaptive, space-efficient

This work:

Supplementary methods to improve RPE performance.

<sup>1</sup>S. Kimmel, G. H. Low, and T. J. Yoder, Phys. Rev. A 92, 062315 (2015).

## Schematic for an RPE error estimation method:

- Apply composite operator  $k$  times to some initial state.
- Measure in one of a pair of bases (1 or 2).
- Design such that success probabilities are given by...

$$P_1(k) = \frac{1}{2} + \frac{1}{2} \cos(kA) + \delta_1(k),$$
$$P_2(k) = \frac{1}{2} + \frac{1}{2} \sin(kA) + \delta_2(k),$$

for  $A$  an invertible function of the desired error parameter, and  $\delta_i(k)$  some additive deviations.

# Robust phase estimation

Ideal success probabilities:

$$P_1(k) = \frac{1}{2} + \frac{1}{2} \cos(kA), \quad P_2(k) = \frac{1}{2} + \frac{1}{2} \sin(kA).$$

- Sample at  $k_i = 2^i$  for  $i = 0, 1, 2, \dots$
- Take  $M_i$  measurements at  $k_i$  to obtain estimate  $\hat{A}_i$  of  $A$ :

$$A \approx \hat{A}_i \text{ modulo } \frac{2\pi}{2^i},$$

with error  $\sigma(\hat{A}_i) \propto \frac{1}{k_i \sqrt{M_i}} = \frac{2^{-i}}{\sqrt{M_i}}$ .

Principal ranges:

Choose the (unique)  $\hat{A}_i$  such that  $|\hat{A}_i - \hat{A}_{i-1}| < 2^{-i}\pi$ , for  $i = 1, 2, 3, \dots$

## Drawback:

RPE error estimate assumes only statistical errors, but decoherent errors can systematically alter signal waveform.

Can cause effective parameter estimated to be different from desired parameter, in two ways:

- Effective parameter depends on sequence  $\{k_i\}$ : we show how to catch this!
- Effective parameter independent of sequence  $\{k_i\}$ : alteration to period of signal.

# Catching failures in RPE

Idea:

Sample at second sequence of  $k$  values:

$$k'_i = k_i + f(i),$$

where  $\frac{1}{2}f(i+1) \leq f(i) \leq 2^i$  for all  $i$ . Call resulting estimates  $\hat{B}_i$ .

Then for each  $i$ , check that  $|\hat{B}_i - \hat{A}_i| \leq \frac{2\pi}{2^i}$ :

- If false for some  $i$ , then

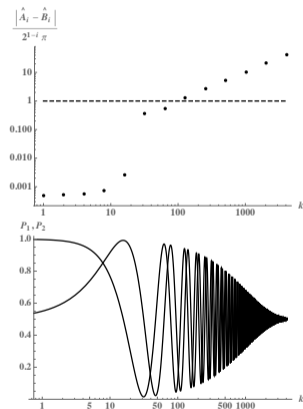
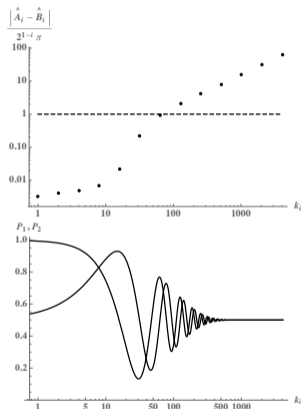
$$|\hat{A}_i - A| > \frac{\pi}{2^i} = \frac{\pi}{k_i}, \text{ or } |\hat{B}_i - A| > \frac{\pi}{2^i} > \frac{\pi}{k'_i} \Rightarrow \text{Failure!}$$

- If true for all  $i$  up to some  $J$ , then for effective target values  $A'$  and  $B'$ ,

$$P \left[ |B' - A'| > \frac{4\pi}{2^J} \right] < \frac{2}{\sqrt{2\pi M_J} 2^{M_J}}.$$

# Catching failures in RPE

**Example:** Catching failures due to depolarization. Catch condition is  $\frac{|\hat{B}_i - \hat{A}_i|}{2^{1-i}\pi} > 1$ :



In these examples,  $f(i) = 2^{i-1}$ . Decay constants:  $b = 0.1A$  (left),  $b = 0.01A$  (right).

# Advantages, Limitations, and Future Work

## Advantages:

- Can avoid systematic errors that would otherwise throw off estimate.
- Does not require denser sampling than original protocol.

## Limitations:

- Adversary who knows offset function  $f$  can fool us.
- Cannot catch alteration to period.

## Future work:

- Optimize choice for  $f$ ?
- Systematic error-specific methods to handle period alteration (some exist).



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